IEC 61300-2-14

Edition 4.0 2021-02
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INTERNATIONAL STANDARD

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Fibre optic interconnecting devices and passive components – Basic test and measurement procedures –
Part 2-14: Tests – High optical power

IEC 61300-2-14:2021-02 RLV(en)

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ICS 33.180.20

ISBN 978-2-8322-9433-8

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FIBRE OPTIC INTERCONNECTING DEVICES AND PASSIVE COMPONENTS – BASIC TEST AND MEASUREMENT PROCEDURES –

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FOREWORD

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This redline version of the official IEC Standard allows the user to identify the changes made to the previous edition IEC 61300-2-14:2012. A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text.

International Standard IEC 61300-2-14 has been prepared by subcommittee 86B: Fibre optic interconnecting devices and passive components, of IEC technical committee 86: Fibre optics.

This fourth edition cancels and replaces the third edition published in 2012. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) harmonizing IEC 61300-1:2016 and IEC 61300-3-4:2012;
b) addition of abbreviated terms;
c) addition of Clause A.2 regarding input optical power from both ends.

The text of this International Standard is based on the following documents:

CDV	Report on voting
86B/4299/CDV	86B/4362A/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61300 series, published under the general title *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures,* can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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FIBRE OPTIC INTERCONNECTING DEVICES AND PASSIVE COMPONENTS – BASIC TEST AND MEASUREMENT PROCEDURES –

Part 2-14: Tests – High optical power

1 Scope

This part of IEC 61300 describes a procedure for determining the suitability of a fibre optic interconnecting device or a passive component to withstand ~~the~~ exposure to the optical power which ~~may occur~~ occurs during its operation.

~~NOTE General information and guidance concerning relevant test and measurement procedures is contained in IEC 61300-1.~~

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60825-1, *Safety of laser products – Part 1: Equipment classification and requirements*

IEC 61300-1, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 1: General and guidance*

IEC 61300-3-1, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-1: Examinations and measurements – Visual examination*

IEC 61300-3-3, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-3: Examinations and measurements – Active monitoring of changes in attenuation and return loss*

IEC 61300-3-35, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-35: Examinations and measurements – ~~Fibre optic connector endface visual and automated inspection~~ Visual inspection of fibre optic connectors and fibre-stub transceivers*

3 Terms, definitions and abbreviated terms

3.1 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp

3.2 Abbreviated terms

CWDM course wavelength division multiplexing
DAS data acquisition system
DUT device under test
DWDM dense wavelength division multiplexing
IL insertion loss
ISO optical isolator
LD laser diode
OSA optical spectrum analyzer
PDL polarization dependent loss
RL return loss
TLS tunable light source
WDL wavelength dependent loss
WDM wavelength division multiplexing
WWDM wide wavelength division multiplexing

4 Apparatus

4.1 Source (S)

The source unit consists of an optical emitter, the means to connect to it and the associated drive electronics. A tunable light source (TLS) in which a specific output wavelength can be tuned may be chosen as the optical emitter. A TLS may consist of a tunable LD and an optical amplifier or a fibre ring laser ~~in order to get an efficient power to test~~. Generally, the power and stability requirements of the test will necessitate that the ~~means to connect to the~~ optical emitter ~~be~~ has a fibre pigtail. It shall ~~be~~ have a stable ~~in~~ output power and wavelength/frequency over the measurement period. For DWDM devices, the frequency ~~uncertainty~~ stability (instead of the wavelength ~~uncertainty~~ stability) shall be less than half of the channel bandwidth. Unless otherwise stated in the relevant specification, the source shall have the following characteristics:

a) centre wavelength ~~uncertainty including~~ stability:
   – nominal centre wavelength ±5 nm (for WWDM and CWDM devices);
b) centre frequency ~~uncertainty~~ stability:
   – nominal centre frequency ±6,3 GHz (for DWDM devices of 25 GHz channel bandwidth);
   – nominal centre frequency ±12,5 GHz (for DWDM devices of 50 GHz channel bandwidth);
   – nominal centre frequency ±25 GHz (for DWDM devices of 100 GHz channel bandwidth);
c) output power ~~uncertainty and~~ stability:
   – nominal output power ±0,05 dB.

4.2 Optical detector (D)

The optical detector unit ~~is an optical power meter and~~ consists of an optical detector, the means to connect to it and the associated electronics. The detector~~s~~ shall have sufficient dynamic range to make the necessary measurements and shall be linear over the measurement range. The detector~~s~~ shall be stable over the measurement period and shall have an operational wavelength range consistent with the DUT. The connection to the detector~~s~~ shall be an adaptor that accepts a connector plug of the appropriate design. The detector~~s~~ shall be capable of capturing all light emitted by the connector plug. Unless otherwise stated in the relevant specification, the detector~~s~~ shall have the following characteristics:

~~– linearity: ≤ ±0,1 dB;~~

~~– uncertainty including polarization dependency: ≤ ±0,05 dB;~~

~~– resolution: ≤ ±0,01 dB.~~

– maximum nonlinearity: ≤ ±0,1 dB;

– accuracy including polarization dependency: ≤ ±0,05 dB;

– resolution: ≤ 0,01 dB.

4.3 Environmental chamber

The test set-up shall include an environmental chamber capable of producing and maintaining the specified temperature and/or humidity.

4.4 Data acquisition system (DAS)

Recording the optical power readings of the optical ~~power readings at the optical~~ detector may be done either manually or automatically. An appropriate DAS shall be used where measurements are performed automatically.

4.5 Branching device (BD)

The splitting ratio of the branching device shall be stable over the optical powers and wavelengths chosen for the test. It shall also be insensitive to polarization. ~~The branching devices shall be stable during the test. The splitting ratio of 1:99 for branching devices is recommended in order to input high power to the DUT and low power to the optical detector.~~ A splitting ratio of 1:99 is recommended for the branching device in order to input high power to the DUT and low power to the optical detector.

4.6 Temporary joints (TJ)

These are typically used in connecting the device under test to the test apparatus. ~~Generally,~~ For the test requirements of optical power and stability ~~requirements of a test will necessitate that~~, the temporary joints shall be fusion splices.

4.7 Safety devices

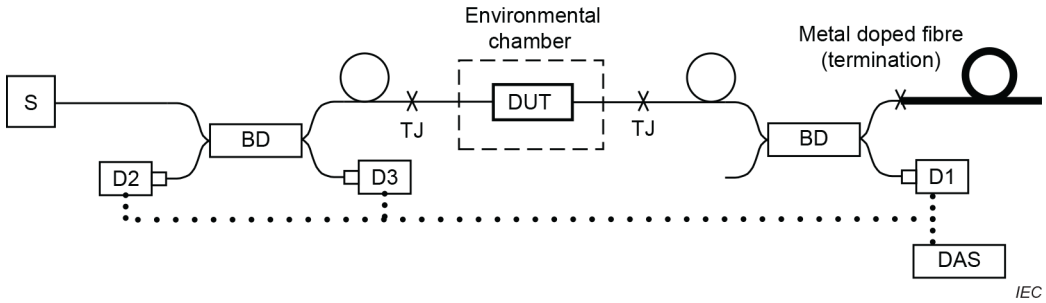
All necessary safety devices, including laser safety glasses, signs and other safety materials, shall be provided in order to protect individuals from possible hazards during testing.

4.8 Test set-up

For two-port optical components, a typical layout for the test apparatus is shown in Figure 1.

This test procedure involves the use of optical powers which constitute a potential ocular and skin hazard to test personnel. All necessary safety procedures shall be adopted in accordance with IEC 60825-1. In particular, the DUT shall be unpowered (that is, with no power propagating in the fibre) when conducting a visual examination.

Optical connectors shall not be used. Fusion splices shall be used for all connecting points as described in 4.6.



Key

BD branching device
D detector
DAS data acquisition system
DUT device under test
S light source
TJ temporary joint

Figure 1 – Typical optical power test set-up

For multiport devices such as branching devices, all combinations of input and output ports shall be tested, unless otherwise stated in the relevant specification.

For WDM devices, ~~multi-wavelength~~ multiple wavelengths shall be input at the same time according to the application. Clause A.1 describes an example of the test set-up for WDM devices.

~~To minimize test equipments, the DUTs can be connected as a series.~~ To minimize test equipment, the DUTs may be connected in series. Clause A.2 describes an example of the test set-up for ~~a series connection of~~ series-connected DUTs.

5 Procedure

5.1 Preconditioning

The chosen test samples shall be representative of a standard product.

Prepare and clean the DUTs according to the manufacturer's instructions. Visual examination shall be undertaken in accordance with IEC 61300-3-1 and IEC 61300-3-35. Debris or the presence of contamination is one of the primary causes of failure in high optical power connector applications.

NOTE IEC TR 62627-01 describes fibre optic connector cleaning methods.

Precondition the DUTs for 2 h or more at the standard atmospheric conditions as defined in IEC 61300-1, unless otherwise specified in the relevant specification.

5.2 Initial examinations and measurements

~~Complete~~ Perform initial examinations and measurements on the DUTs as required by the relevant specification. The results of the initial measurements shall be within the limits established in the relevant specification.

5.3 Conditioning

a) Set the chamber and the DUT to the standard atmospheric conditions. Place the DUT in the chamber in its normal operating position. The hook-ups of the DUT to the peripheral equipment shall also be placed in their normal operating position, where required.

b) ~~Adjust~~ Set the chamber temperature and humidity to the specified ~~severity~~ severities (see 6.4 and 6.5). The rate of change of temperature shall not exceed 1 °C/min, averaged over a maximum period of 5 min. Allow the DUT to reach the set stable temperature and maintain the temperature for the exposure time.

c) Set the wavelength and optical power to be input to the DUT and turn on the optical source and input optical power to the DUT.

d) Continue to input the optical power to the DUT for the exposure time specified ~~in severity~~ (see 6.6). Monitor the changes in attenuation and return loss of the DUT according to IEC 61300-3-3 during the exposure time. The changes shall be within the pass criteria specified in the relevant specification (see Annexe B).

NOTE Optical power absorption within the DUT can cause its internal temperature to rise leading to a change in attenuation. The duration of changing attenuation depends on the absorption rate and the thermal capacity of the DUT. Examples of the high power test results are described in IEC TR 62627-03-02 and IEC TR 62627-03-03.

e) At the completion of the exposure time, stop inputting the optical power and change the temperature in the chamber to the standard atmospheric condition. Continue to maintain the DUT in the chamber while the temperature is gradually changed.

5.4 Recovery

Allow the DUT to remain under the standard atmospheric condition for 2 h or more, as defined in IEC 61300-1, unless otherwise specified in the relevant specification.

5.5 Final examinations and measurements

On completion of the test, remove all fixtures and make final examinations and measurements on the DUT, as required by the relevant specification, to ensure that there is no permanent damage to the DUT. Clean the DUT according to the manufacturer's instructions. The results of the final measurement shall be within the limit established in the relevant specification.

Unless otherwise specified in the relevant specification, visually examine the DUT in accordance with IEC 61300-3-1. Check for evidence of any degradation in the DUT. ~~This may~~ These include, for example:

a) broken, loose or damaged parts or accessories;

b) breaking or damage to the cable jacket, seals, strain relief or fibres;

c) displaced, bent, or broken parts.

6 Severity

6.1 General

Severity is a combination of an optical power, a wavelength, a temperature, humidity and an exposure time. The severity shall be specified in the relevant specification.

NOTE IEC TR 62627-03-04 gives guidelines for high optical power testing.

6.2 Optical power

The optical power of the test shall be decided in consideration of the application, unless otherwise stated in the relevant specification. ~~The following optical powers are examples~~ The recommended power levels for testing are:

10 mW, 30 mW, 50 mW, 100 mW, 300 mW and 500 mW.

6.3 Wavelengths

The test wavelength shall be the centre or typical wavelength of all operating wavelength ranges specified in the relevant specification. ~~The following wavelengths are examples~~ The recommended wavelengths for testing are:

980 nm, 1 310 nm, 1 490 nm, 1 510 nm, 1 550 nm, 1 580 nm, 1 610 nm, 1 625 nm and 1 650 nm.

For WDM devices, the combinations of multi-wavelengths which are input at the same time shall be decided in consideration of the application, unless otherwise stated in the relevant specification.

6.4 Temperature

Unless otherwise stated in the relevant specification, the test temperature shall be the maximum temperature of the operating temperature range specified in the relevant specification.

6.5 Humidity

Unless otherwise stated in the relevant specification, the test humidity shall be controlled at the maximum humidity of the operating humidity range specified in the relevant specification.

~~In case the DUT is hermetically seal-packaged, the test humidity does not need to be controlled.~~

6.6 Exposure time

The test exposure time shall be decided in consideration of the thermal capacity of the DUT. For a small component whose weight is ~~approximately~~ less than 0,1 kg, a test exposure time of 30 min is recommended.

7 Details to be specified

The following details, as applicable, shall be specified in the relevant specification:

a) optical power;
b) wavelengths;
c) temperature;
d) humidity;
e) exposure time;
f) initial examinations, initial measurements and initial performance requirements;
g) examinations during test, measurements during test and performance requirements during test;
h) final examinations, final measurements and final performance requirements;
i) deviations from test procedure;
j) additional pass/fail criteria;
k) number of ports and combinations of input and output ports;
l) combinations of ~~multi-~~multiple wavelengths which are input at the same time for WDM devices.

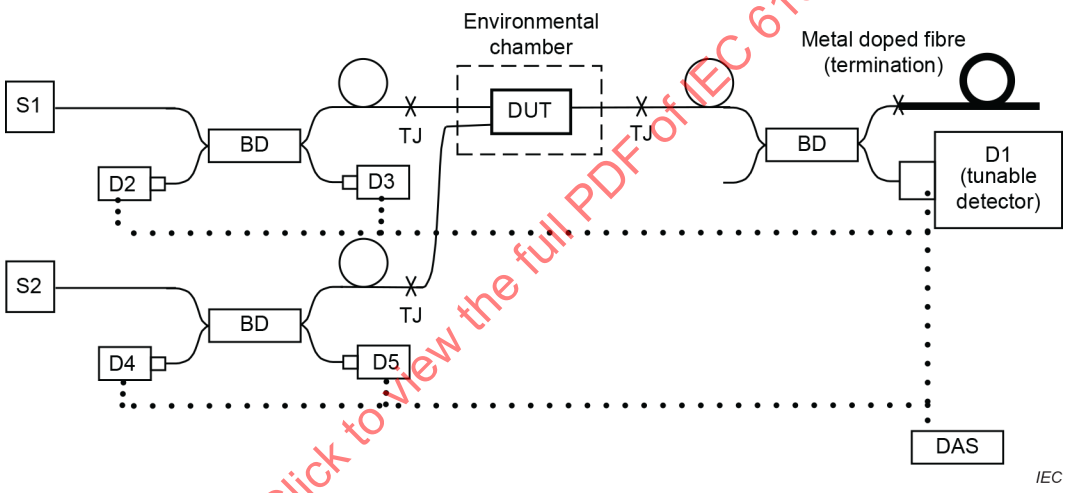
Annex A
(normative)

Examples of test set-up

A.1 WDM devices

For WDM devices, ~~multi-wavelength shall be~~ multiple wavelengths are input at the same time according to the application. For two inputs/one output WDM components, an example layout for the test apparatus is shown in Figure A.1.

The optical power of the first wavelength is input from the source S1. In addition, the optical power of the second wavelength is input from the source S2 at the same time. The optical power ratio of the first wavelength and second wavelength shall be stated in the relevant specification, based on the application. In Figure A.1, the attenuation changes for the first wavelength and second wavelength are monitored at the wavelength tunable optical detector D1, respectively. For the tunable optical detector D1, an OSA (optical spectrum analyzer), or a combination of a tunable filter and an optical power meter, is recommended.



Key

BD branching device
D detector
DAS data acquisition system
DUT device under test
S light source
TJ temporary joint

Figure A.1 – Example of optical power test set-up for a 2 x 1 WDM device

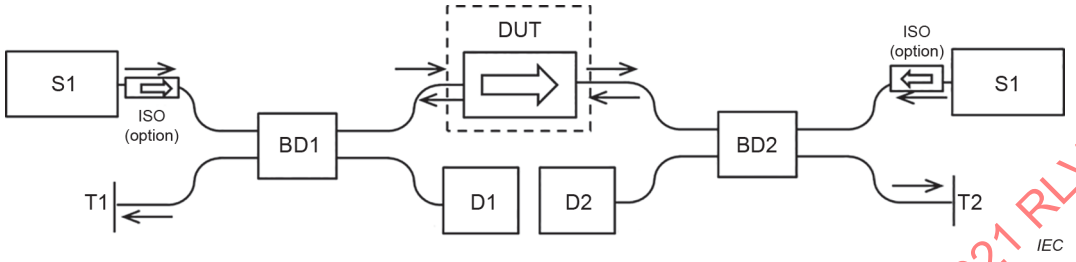
A.2 Input optical power from both ends

When optical power input into both ends of the DUT is required, two light sources, two branching devices and two detectors shall be used (see Figure A.2). To prevent optical power fluctuation, it is recommended that optical isolators be used with each light source.

It is difficult to monitor the optical output power during the test. Therefore, the optical performance, such as insertion loss (attenuation), return loss and isolation, shall be measured before the test.

During the test, any input power changes of the light sources S1 and S2 are monitored by detectors D1 and D2, respectively.

After the test, the DUT's optical performance shall be measured. The performance changes shall be calculated.



Key

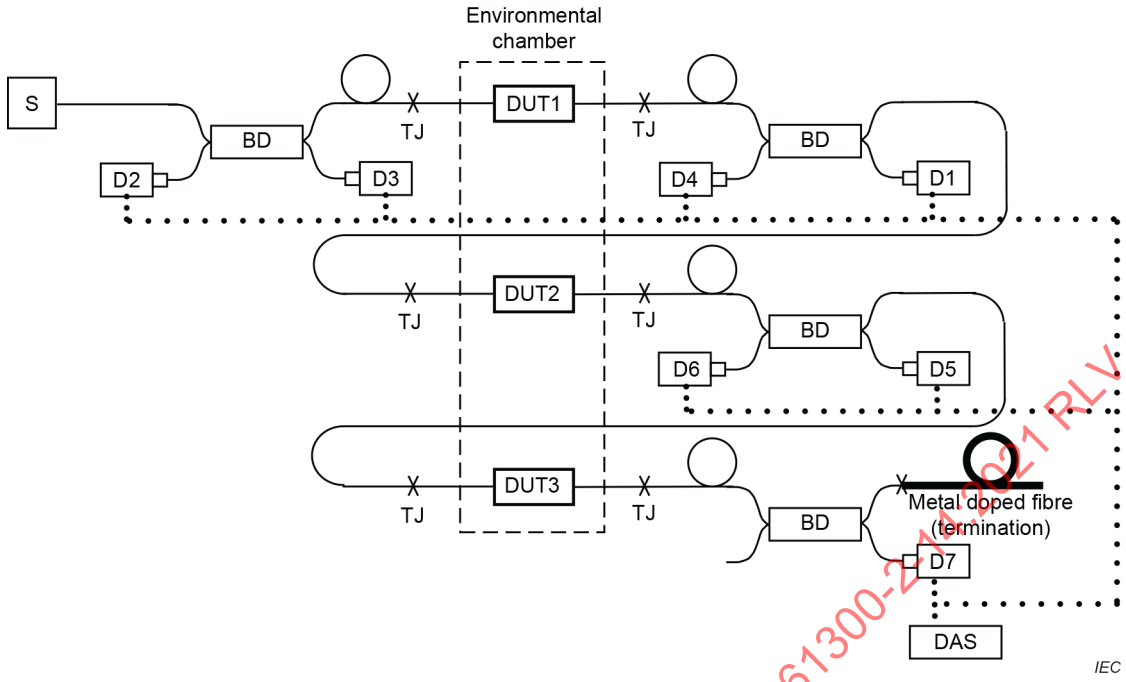
BD	branching device
D	detector
DUT	device under test
ISO	optical isolator
S	light source
T	termination

Figure A.2 – Example of test set-up of both direction input test

A.3 Series connection set-up

~~To minimize test equipments, the DUT can be connected as a series.~~ To minimize test equipment, DUTs may be connected in series. To test three DUTs simultaneously, an example layout for the test apparatus is shown in Figure A.3.

In this set-up, the optical power input to the last DUT, for example DUT3 in Figure A.3, shall be equal or higher than the optical power specified in the relevant specification.



Key

BD branching device

D detector

DAS data acqusition system

DUT device under test

S light source

TJ temporary joint

Figure A.3 – Example of optical power test set-up in series connection

Annex B
(informative)

Examples of pass/fail criteria during exposure time

B.1 General

~~During the exposure time of the optical power, only the changes in attenuation and return loss can be measured according to IEC 61300-3-3. It shall be noted that polarization dependent loss (PDL) and wavelength dependent loss (WDL) are difficult to monitor and the measurement uncertainty might be larger than the initial and final measurements according to IEC 61300-3-4 or some other standards in the IEC 61300 series.~~

During the exposure time of the optical power, only the changes in attenuation and return loss can be measured according to IEC 61300-3-3. It is noted that the polarization dependent loss (PDL) and the wavelength dependent loss (WDL) can affect the measurement uncertainty of insertion loss (IL) change and the return loss (RL) change during the test, and PDL and WDL are difficult to monitor during the test.

Therefore, the measurement uncertainties of the IL change and RL change during the test can be larger than those of the differences of those measured before and after the test according to IEC 61300-3-4 or some other standards in the IEC 61300 series.

B.2 Attenuation limitation of monitoring

The pass/fail criteria for attenuation limitation during the exposure ~~shall~~ should include a consideration of uncertainties caused by PDL, WDL and the measurement system itself, in order to prevent the misclassification of a DUT within the limitation being misjudged as a failure DUT. This attenuation limitation of monitoring could pass over some DUTs, with slightly high attenuation, from being classified as failure; however, some of those DUTs could be marked as a failure in the final measurement.

An example of attenuation limitation of monitoring $A_{\text{limit,mon}}$ (dB) is:

~~$$A_{\text{limit,mon}} = A_{\text{limit,offline}} + A_{\text{PDL}} + A_{\text{WDL}} + A_{\text{error}}$$~~

$$A_{\text{limit,mon}} = A_{\text{limit,offline}} + A_{\text{PDL}} + A_{\text{WDL}} + A_{\text{uncer}}$$

where

$A_{\text{limit,offline}}$ is the original attenuation limitation of offline measurement for initial and final measurement (dB);

A_{PDL} is the PDL of the DUT or a constant specified in the relevant specification (dB);

A_{WDL} is the WDL of the DUT or a constant specified in the relevant specification (dB);

A_{uncer} is the value based on the measurement uncertainty of the system including light source stability, detector uncertainty including nonlinearity, accuracy, polarization dependency and resolution, and losses of temporary joints (dB).

~~A_{error} is the value based on the measurement error of the system including light source stability, detector uncertainty and losses of temporary joints (dB).~~

During monitoring, the change of attenuation ΔA (dB) ~~should be~~ is within the following formula:

$$\Delta A(t) \leq A_{\text{limit,offline}} - A_{0,\text{ini}}$$

where

$A_{0,\text{ini}}$ is the attenuation of the DUT measured in the initial measurement according to IEC 61300-3-4;

$\Delta A(t)$ is the change of attenuation calculated from the measured optical power change as $\Delta A(t) = P(t) - P(t = 0)$;

$P(t = 0)$ is the measured output optical power at the first measurement of monitoring;

$P(t)$ is the measured output optical power at the time of t.

B.3 Return loss limitation

The pass/fail criteria for return loss during the exposure could be specified by a similar method.

Sometimes, the measurement system used for high optical power is not suitable for the measurement of very high return loss limitation specified for initial and final measurement. In such a case, another pass/fail criterion ~~shall~~ should be adopted. An example is described in Clause B.4.

B.4 Judgment based on the change

These examples of pass/fail criteria could be adopted as additional or alternative requirements for Clause B.1 and Clause B.2. During monitoring, the change of attenuation ΔA (dB) and the change of return loss ΔRL (dB) ~~shall~~ should be within the following ~~requirements~~ recommendations:

– for a component with an initial insertion loss of less than 1,0 dB, $\Delta A \leq 0{,}3$ dB;

– for a component with an initial insertion loss of less than 2,0 dB, $\Delta A \leq 0{,}5$ dB;

– for a component with an initial insertion loss of 2,0 dB or more, and less than 10,0 dB, $\Delta A \leq 1{,}0$ dB;

– for a component with an initial insertion loss of 10,0 dB or more, $\Delta A \leq 2{,}0$ dB;

– $|\Delta RL| \leq 10{,}0$ dB.

where the initial insertion loss is measured in the initial measurement.

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IEC TR 62627-01, *Fibre optic interconnecting devices and passive components – Part 01: Fibre optic connector cleaning methods*

IEC TR 62627-03-02, *Fiber optic interconnecting devices and passive components – Part 03-02: Reliability – Report of high power transmission test of specified passive optical components*

IEC TR 62627-03-03, *Fibre optic interconnecting devices and passive components – Part 03-03: Reliability – Report on high-power reliability for metal-doped optical fibre plug-style optical attenuators*

IEC TR 62627-03-04, *Fibre optic interconnecting devices and passive components – Part 03-04: Reliability – Guideline for high power reliability of passive optical components*

IEC 61300-2-14

Edition 4.0 2021-02

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Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-14: Tests – High optical power

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Part 2-14: Tests – High optical power

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International Standard IEC 61300-2-14 has been prepared by subcommittee 86B: Fibre optic interconnecting devices and passive components, of IEC technical committee 86: Fibre optics.

This fourth edition cancels and replaces the third edition published in 2012. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) harmonizing IEC 61300-1:2016 and IEC 61300-3-4:2012;
b) addition of abbreviated terms;
c) addition of Clause A.2 regarding input optical power from both ends.

The text of this International Standard is based on the following documents:

CDV	Report on voting
86B/4299/CDV	86B/4362A/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61300 series, published under the general title *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures,* can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

FIBRE OPTIC INTERCONNECTING DEVICES AND PASSIVE COMPONENTS – BASIC TEST AND MEASUREMENT PROCEDURES –

Part 2-14: Tests – High optical power

1 Scope

This part of IEC 61300 describes a procedure for determining the suitability of a fibre optic interconnecting device or a passive component to withstand exposure to the optical power which occurs during its operation.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60825-1, *Safety of laser products – Part 1: Equipment classification and requirements*

IEC 61300-1, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 1: General and guidance*

IEC 61300-3-1, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-1: Examinations and measurements – Visual examination*

IEC 61300-3-3, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-3: Examinations and measurements – Active monitoring of changes in attenuation and return loss*

IEC 61300-3-35, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-35: Examinations and measurements – Visual inspection of fibre optic connectors and fibre-stub transceivers*

3 Terms, definitions and abbreviated terms

3.1 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp

3.2 Abbreviated terms

CWDM course wavelength division multiplexing

DAS data acquisition system

DUT device under test

DWDM	dense wavelength division multiplexing
IL	insertion loss
ISO	optical isolator
LD	laser diode
OSA	optical spectrum analyzer
PDL	polarization dependent loss
RL	return loss
TLS	tunable light source
WDL	wavelength dependent loss
WDM	wavelength division multiplexing
WWDM	wide wavelength division multiplexing

4 Apparatus

4.1 Source (S)

The source unit consists of an optical emitter, the means to connect to it and the associated drive electronics. A tunable light source (TLS) in which a specific output wavelength can be tuned may be chosen as the optical emitter. A TLS may consist of a tunable LD and an optical amplifier or a fibre ring laser. Generally, the power and stability requirements of the test will necessitate that the optical emitter has a fibre pigtail. It shall have a stable output power and wavelength/frequency over the measurement period. For DWDM devices, the frequency stability (instead of the wavelength stability) shall be less than half of the channel bandwidth. Unless otherwise stated in the relevant specification, the source shall have the following characteristics:

a) centre wavelength stability:
   – nominal centre wavelength ±5 nm (for WWDM and CWDM devices);
b) centre frequency stability:
   – nominal centre frequency ±6,3 GHz (for DWDM devices of 25 GHz channel bandwidth);
   – nominal centre frequency ±12,5 GHz (for DWDM devices of 50 GHz channel bandwidth);
   – nominal centre frequency ±25 GHz (for DWDM devices of 100 GHz channel bandwidth);
c) output power stability:
   – nominal output power ±0,05 dB.

4.2 Optical detector (D)

The optical detector unit consists of an optical detector, the means to connect to it and the associated electronics. The detector shall have sufficient dynamic range to make the necessary measurements and shall be linear over the measurement range. The detector shall be stable over the measurement period and shall have an operational wavelength range consistent with the DUT. The connection to the detector shall be an adaptor that accepts a connector plug of the appropriate design. The detector shall be capable of capturing all light emitted by the connector plug. Unless otherwise stated in the relevant specification, the detector shall have the following characteristics:

– maximum nonlinearity: ≤ ±0,1 dB;
– accuracy including polarization dependency: ≤ ±0,05 dB;
– resolution: ≤ 0,01 dB.

4.3 Environmental chamber

The test set-up shall include an environmental chamber capable of producing and maintaining the specified temperature and/or humidity.

4.4 Data acquisition system (DAS)

Recording the optical power readings of the optical detector may be done either manually or automatically. An appropriate DAS shall be used where measurements are performed automatically.

4.5 Branching device (BD)

The splitting ratio of the branching device shall be stable over the optical powers and wavelengths chosen for the test. It shall also be insensitive to polarization. A splitting ratio of 1:99 is recommended for the branching device in order to input high power to the DUT and low power to the optical detector.

4.6 Temporary joints (TJ)

These are typically used in connecting the device under test to the test apparatus. For the test requirements of optical power and stability, the temporary joints shall be fusion splices.

4.7 Safety devices

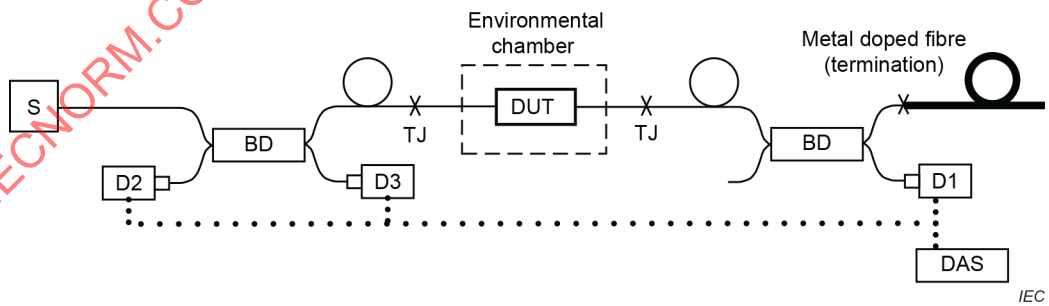
All necessary safety devices, including laser safety glasses, signs and other safety materials, shall be provided in order to protect individuals from possible hazards during testing.

4.8 Test set-up

For two-port optical components, a typical layout for the test apparatus is shown in Figure 1.

This test procedure involves the use of optical powers which constitute a potential ocular and skin hazard to test personnel. All necessary safety procedures shall be adopted in accordance with IEC 60825-1. In particular, the DUT shall be unpowered (that is, with no power propagating in the fibre) when conducting a visual examination.

Optical connectors shall not be used. Fusion splices shall be used for all connecting points as described in 4.6.



Key

BD	branching device
D	detector
DAS	data acquisition system
DUT	device under test
S	light source
TJ	temporary joint

Figure 1 – Typical optical power test set-up

For multiport devices such as branching devices, all combinations of input and output ports shall be tested, unless otherwise stated in the relevant specification.

For WDM devices, multiple wavelengths shall be input at the same time according to the application. Clause A.1 describes an example of the test set-up for WDM devices.

To minimize test equipment, the DUTs may be connected in series. Clause A.2 describes an example of the test set-up for series-connected DUTs.

5 Procedure

5.1 Preconditioning

The chosen test samples shall be representative of a standard product.

Prepare and clean the DUTs according to the manufacturer's instructions. Visual examination shall be undertaken in accordance with IEC 61300-3-1 and IEC 61300-3-35. Debris or the presence of contamination is one of the primary causes of failure in high optical power connector applications.

NOTE IEC TR 62627-01 describes fibre optic connector cleaning methods.

Precondition the DUTs for 2 h or more at the standard atmospheric conditions as defined in IEC 61300-1, unless otherwise specified in the relevant specification.

5.2 Initial examinations and measurements

Perform initial examinations and measurements on the DUTs as required by the relevant specification. The results of the initial measurements shall be within the limits established in the relevant specification.

5.3 Conditioning

a) Set the chamber and the DUT to the standard atmospheric conditions. Place the DUT in the chamber in its normal operating position. The hook-ups of the DUT to the peripheral equipment shall also be placed in their normal operating position, where required.

b) Set the chamber temperature and humidity to the specified severities (see 6.4 and 6.5). The rate of change of temperature shall not exceed 1 °C/min, averaged over a maximum period of 5 min. Allow the DUT to reach the set stable temperature and maintain the temperature for the exposure time.

c) Set the wavelength and optical power to be input to the DUT and turn on the optical source and input optical power to the DUT.

d) Continue to input the optical power to the DUT for the exposure time specified (see 6.6). Monitor the changes in attenuation and return loss of the DUT according to IEC 61300-3-3 during the exposure time. The changes shall be within the pass criteria specified in the relevant specification (see Annexe B).

NOTE Optical power absorption within the DUT can cause its internal temperature to rise leading to a change in attenuation. The duration of changing attenuation depends on the absorption rate and the thermal capacity of the DUT. Examples of the high power test results are described in IEC TR 62627-03-02 and IEC TR 62627-03-03.

e) At the completion of the exposure time, stop inputting the optical power and change the temperature in the chamber to the standard atmospheric condition. Continue to maintain the DUT in the chamber while the temperature is gradually changed.

5.4 Recovery

Allow the DUT to remain under the standard atmospheric condition for 2 h or more, as defined in IEC 61300-1, unless otherwise specified in the relevant specification.

5.5 Final examinations and measurements

On completion of the test, remove all fixtures and make final examinations and measurements on the DUT, as required by the relevant specification, to ensure that there is no permanent damage to the DUT. Clean the DUT according to the manufacturer's instructions. The results of the final measurement shall be within the limit established in the relevant specification.

Unless otherwise specified in the relevant specification, visually examine the DUT in accordance with IEC 61300-3-1. Check for evidence of any degradation in the DUT. These include, for example:

a) broken, loose or damaged parts or accessories;

b) breaking or damage to the cable jacket, seals, strain relief or fibres;

c) displaced, bent, or broken parts.

6 Severity

6.1 General

Severity is a combination of an optical power, a wavelength, a temperature, humidity and an exposure time. The severity shall be specified in the relevant specification.

NOTE IEC TR 62627-03-04 gives guidelines for high optical power testing.

6.2 Optical power

The optical power of the test shall be decided in consideration of the application, unless otherwise stated in the relevant specification. The recommended power levels for testing are:

10 mW, 30 mW, 50 mW, 100 mW, 300 mW and 500 mW.

6.3 Wavelengths

The test wavelength shall be the centre or typical wavelength of all operating wavelength ranges specified in the relevant specification. The recommended wavelengths for testing are:

980 nm, 1 310 nm, 1 490 nm, 1 510 nm, 1 550 nm, 1 580 nm, 1 610 nm, 1 625 nm and 1 650 nm.

For WDM devices, the combinations of multi-wavelengths which are input at the same time shall be decided in consideration of the application, unless otherwise stated in the relevant specification.

6.4 Temperature

Unless otherwise stated in the relevant specification, the test temperature shall be the maximum temperature of the operating temperature range specified in the relevant specification.

6.5 Humidity

Unless otherwise stated in the relevant specification, the test humidity shall be controlled at the maximum humidity of the operating humidity range specified in the relevant specification.

6.6 Exposure time

The test exposure time shall be decided in consideration of the thermal capacity of the DUT. For a small component whose weight is less than 0,1 kg, a test exposure time of 30 min is recommended.

7 Details to be specified

The following details, as applicable, shall be specified in the relevant specification:

f) optical power;
g) wavelengths;
h) temperature;
i) humidity;
j) exposure time;
k) initial examinations, initial measurements and initial performance requirements;
l) examinations during test, measurements during test and performance requirements during test;
m) final examinations, final measurements and final performance requirements;
n) deviations from test procedure;
o) additional pass/fail criteria;
p) number of ports and combinations of input and output ports;
q) combinations of multiple wavelengths which are input at the same time for WDM devices.

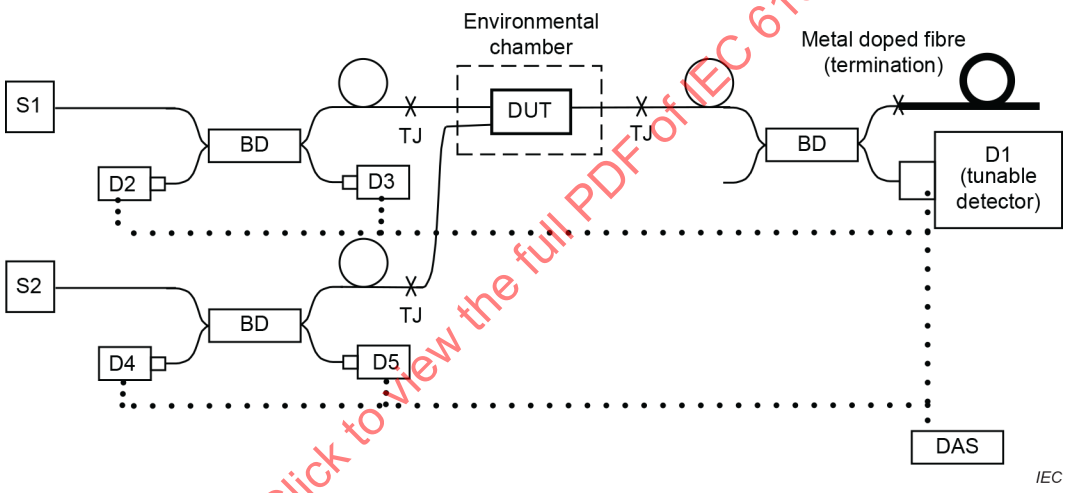
Annex A
(normative)

Examples of test set-up

A.1 WDM devices

For WDM devices, multiple wavelengths are input at the same time according to the application. For two inputs/one output WDM components, an example layout for the test apparatus is shown in Figure A.1.

The optical power of the first wavelength is input from the source S1. In addition, the optical power of the second wavelength is input from the source S2 at the same time. The optical power ratio of the first wavelength and second wavelength shall be stated in the relevant specification, based on the application. In Figure A.1, the attenuation changes for the first wavelength and second wavelength are monitored at the wavelength tunable optical detector D1, respectively. For the tunable optical detector D1, an OSA (optical spectrum analyzer), or a combination of a tunable filter and an optical power meter, is recommended.



Key

BD branching device
D detector
DAS data acquisition system
DUT device under test
S light source
TJ temporary joint

Figure A.1 – Example of optical power test set-up for a 2 x 1 WDM device

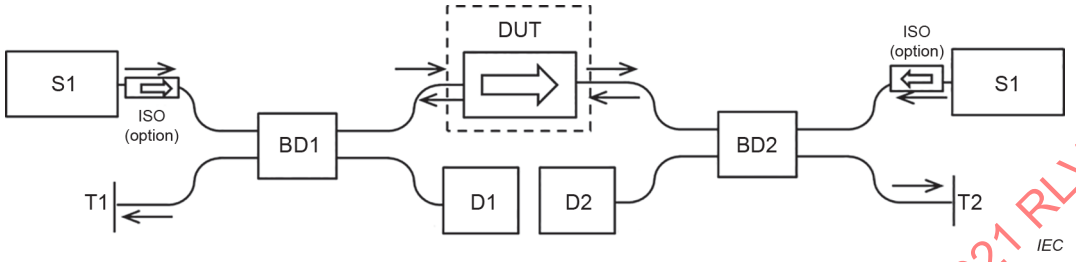
A.2 Input optical power from both ends

When optical power input into both ends of the DUT is required, two light sources, two branching devices and two detectors shall be used (see Figure A.2). To prevent optical power fluctuation, it is recommended that optical isolators be used with each light source.

It is difficult to monitor the optical output power during the test. Therefore, the optical performance, such as insertion loss (attenuation), return loss and isolation, shall be measured before the test.

During the test, any input power changes of the light sources S1 and S2 are monitored by detectors D1 and D2, respectively.

After the test, the DUT's optical performance shall be measured. The performance changes shall be calculated.



Key

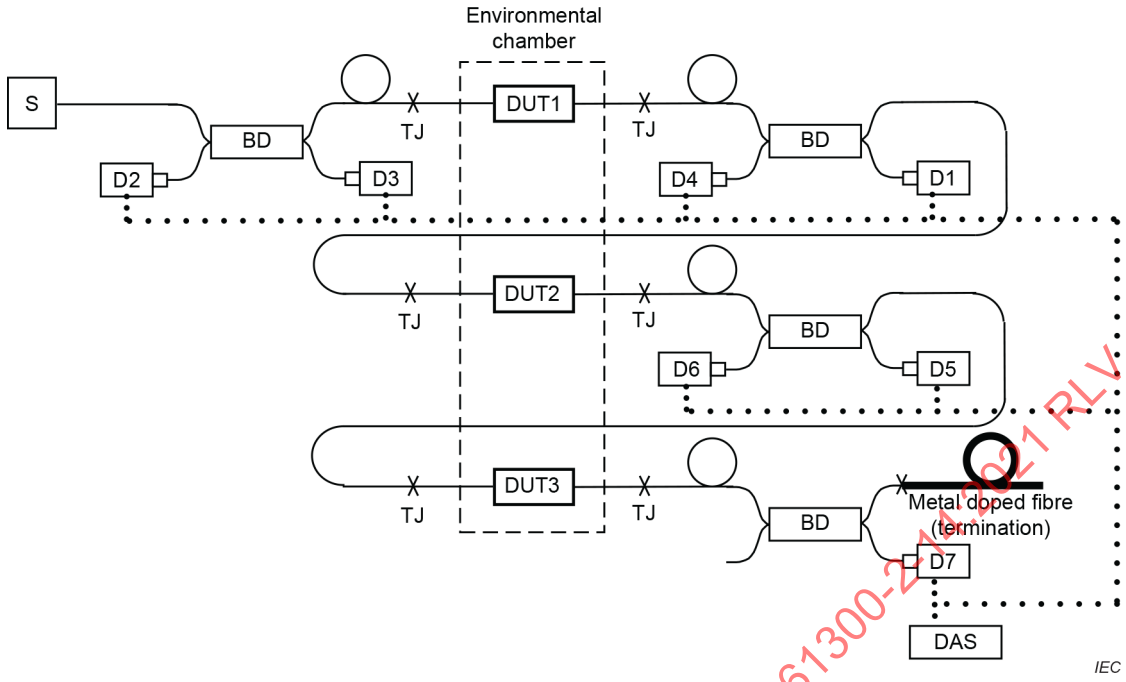
BD	branching device
D	detector
DUT	device under test
ISO	optical isolator
S	light source
T	termination

Figure A.2 – Example of test set-up of both direction input test

A.3 Series connection set-up

To minimize test equipment, DUTs may be connected in series. To test three DUTs simultaneously, an example layout for the test apparatus is shown in Figure A.3.

In this set-up, the optical power input to the last DUT, for example DUT3 in Figure A.3, shall be equal or higher than the optical power specified in the relevant specification.



Key

BD branching device

D detector

DAS data acqusition system

DUT device under test

S light source

TJ temporary joint

Figure A.3 – Example of optical power test set-up in series connection

Annex B
(informative)

Examples of pass/fail criteria during exposure time

B.1 General

During the exposure time of the optical power, only the changes in attenuation and return loss can be measured according to IEC 61300-3-3. It is noted that the polarization dependent loss (PDL) and the wavelength dependent loss (WDL) can affect the measurement uncertainty of insertion loss (IL) change and the return loss (RL) change during the test, and PDL and WDL are difficult to monitor during the test.

Therefore, the measurement uncertainties of the IL change and RL change during the test can be larger than those of the differences of those measured before and after the test according to IEC 61300-3-4 or some other standards in the IEC 61300 series.

B.2 Attenuation limitation of monitoring

The pass/fail criteria for attenuation limitation during the exposure should include a consideration of uncertainties caused by PDL, WDL and the measurement system itself, in order to prevent the misclassification of a DUT within the limitation being misjudged as a failure DUT. This attenuation limitation of monitoring could pass over some DUTs, with slightly high attenuation, from being classified as failure; however, some of those DUTs could be marked as a failure in the final measurement.

An example of attenuation limitation of monitoring $A_{\text{limit,mon}}$ (dB) is:

$$A_{\text{limit,mon}} = A_{\text{limit,offline}} + A_{\text{PDL}} + A_{\text{WDL}} + A_{\text{uncer}}$$

where

$A_{\text{limit,offline}}$ is the original attenuation limitation of offline measurement for initial and final measurement (dB);

A_{PDL} is the PDL of the DUT or a constant specified in the relevant specification (dB);

A_{WDL} is the WDL of the DUT or a constant specified in the relevant specification (dB);

A_{uncer} is the value based on the measurement uncertainty of the system including light source stability, detector uncertainty including nonlinearity, accuracy, polarization dependency and resolution, and losses of temporary joints (dB).

During monitoring, the change of attenuation ΔA (dB) is within the following formula:

$$\Delta A(t) \leq A_{\text{limit,offline}} - A_{0,\text{ini}}$$

where

$A_{0,\text{ini}}$ is the attenuation of the DUT measured in the initial measurement according to IEC 61300-3-4;

$\Delta A(t)$ is the change of attenuation calculated from the measured optical power change as $\Delta A(t) = P(t) - P(t = 0)$;

$P(t = 0)$ is the measured output optical power at the first measurement of monitoring;

$P(t)$ is the measured output optical power at the time of t.

B.3 Return loss limitation

The pass/fail criteria for return loss during the exposure could be specified by a similar method.

Sometimes, the measurement system used for high optical power is not suitable for the measurement of very high return loss limitation specified for initial and final measurement. In such a case, another pass/fail criterion should be adopted. An example is described in Clause B.4.

B.4 Judgment based on the change

These examples of pass/fail criteria could be adopted as additional or alternative requirements for Clause B.1 and Clause B.2. During monitoring, the change of attenuation ΔA (dB) and the change of return loss ΔRL (dB) should be within the following recommendations:

– for a component with an initial insertion loss of less than 1,0 dB, $\Delta A \leq$ 0,3 dB;

– for a component with an initial insertion loss of less than 2,0 dB, $\Delta A \leq$ 0,5 dB;

– for a component with an initial insertion loss of 2,0 dB or more, and less than 10,0 dB, $\Delta A \leq$ 1,0 dB;

– for a component with an initial insertion loss of 10,0 dB or more, $\Delta A \leq$ 2,0 dB;

– $| \Delta RL | \leq$ 10,0 dB.

where the initial insertion loss is measured in the initial measurement.

Bibliography

IEC 61300 (all parts), *Fibre optic interconnecting devices and passive components*

IEC 61300-3-4:2012, *Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 3-4: Examinations and measurements – Attenuation*

IEC 62005-9-4, *Fibre optic interconnecting devices and passive components – Reliability – Part 9-4: High power qualification of passive optical components for environmental category C*

IEC TR 62627-01, *Fibre optic interconnecting devices and passive components – Part 01: Fibre optic connector cleaning methods*

IEC TR 62627-03-02, *Fiber optic interconnecting devices and passive components – Part 03-02: Reliability – Report of high power transmission test of specified passive optical components*

IEC TR 62627-03-03, *Fibre optic interconnecting devices and passive components – Part 03-03: Reliability – Report on high-power reliability for metal-doped optical fibre plug-style optical attenuators*

IEC TR 62627-03-04, *Fibre optic interconnecting devices and passive components – Part 03-04: Reliability – Guideline for high power reliability of passive optical components*

SOMMAIRE

COMMISSION ÉLECTROTECHNIQUE INTERNATIONALE

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DISPOSITIFS D'INTERCONNEXION ET COMPOSANTS PASSIFS FIBRONIQUES – PROCÉDURES FONDAMENTALES D'ESSAIS ET DE MESURES –

Partie 2-14: Essais – Puissance optique élevée

AVANT-PROPOS

1) La Commission Electrotechnique Internationale (IEC) est une organisation mondiale de normalisation composée de l'ensemble des comités électrotechniques nationaux (Comités nationaux de l'IEC). L'IEC a pour objet de favoriser la coopération internationale pour toutes les questions de normalisation dans les domaines de l'électricité et de l'électronique. A cet effet, l'IEC – entre autres activités – publie des Normes internationales, des Spécifications techniques, des Rapports techniques, des Spécifications accessibles au public (PAS) et des Guides (ci-après dénommés "Publication(s) de l'IEC"). Leur élaboration est confiée à des comités d'études, aux travaux desquels tout Comité national intéressé par le sujet traité peut participer. Les organisations internationales, gouvernementales et non gouvernementales, en liaison avec l'IEC, participent également aux travaux. L'IEC collabore étroitement avec l'Organisation Internationale de Normalisation (ISO), selon des conditions fixées par accord entre les deux organisations.
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La Norme internationale IEC 61300-2-14 a été établie par le sous-comité 86B: Dispositifs d'interconnexion et composants passifs à fibres optiques, du comité d'études 86 de l'IEC: Fibres optiques.

Cette quatrième édition annule et remplace la troisième édition parue en 2012. Cette édition constitue une révision technique.

Cette édition inclut les modifications techniques majeures suivantes par rapport à l'édition précédente:

a) harmonisation de l'IEC 61300-1:2016 et de l'IEC 61300-3-4:2012;
b) ajout de termes abrégés;

c) ajout de l'Article A.2 relatif à la puissance optique d'entrée des deux extrémités.

Le texte de cette Norme internationale est issu des documents suivants:

CDV	Rapport de vote
86B/4299/CDV	86B/4362A/RVC

Le rapport de vote indiqué dans le tableau ci-dessus donne toute information sur le vote ayant abouti à l'approbation de cette Norme internationale.

Ce document a été rédigé selon les Directives ISO/IEC, Partie 2.

Une liste de toutes les parties de la série IEC 61300, publiées sous le titre général *Dispositifs d'interconnexion et composants passifs fibroniques – Procédures fondamentales d'essais et de mesures*, est disponible sur le site web de l'IEC.

Le comité a décidé que le contenu de ce document ne sera pas modifié avant la date de stabilité indiquée sur le site web de l'IEC sous "http://webstore.iec.ch" dans les données relatives au document recherché. A cette date, le document sera

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- amendé.

DISPOSITIFS D'INTERCONNEXION ET COMPOSANTS PASSIFS FIBRONIQUES – PROCÉDURES FONDAMENTALES D'ESSAIS ET DE MESURES –

Partie 2-14: Essais – Puissance optique élevée

1 Domaine d'application

La présente partie de l'IEC 61300 décrit une méthode en vue de déterminer l'aptitude d'un dispositif d'interconnexion ou d'un composant passif fibronique à résister à l'exposition à une puissance optique susceptible d'apparaître au cours du fonctionnement.

2 Références normatives

Les documents suivants sont cités dans le texte de sorte qu'ils constituent, pour tout ou partie de leur contenu, des exigences du présent document. Pour les références datées, seule l'édition citée s'applique. Pour les références non datées, la dernière édition du document de référence s'applique (y compris les éventuels amendements).

IEC 60825-1, *Sécurité des appareils à laser – Partie 1: Classification des matériels et exigences*

IEC 61300-1, *Dispositifs d'interconnexion et composants passifs fibroniques – Procédures fondamentales d'essais et de mesures – Partie 1: Généralités et lignes directrices*

IEC 61300-3-1, *Dispositifs d'interconnexion et composants passifs à fibres optiques – Méthodes fondamentales d'essais et de mesures – Partie 3-1: Examens et mesures – Examen visuel*

IEC 61300-3-3, *Dispositifs d'interconnexion et composants passifs à fibres optiques – Méthodes fondamentales d'essais et de mesures – Partie 3-3: Examens et mesures – Contrôle actif des variations de l'affaiblissement et de l'affaiblissement de réflexion*

IEC 61300-3-35, *Dispositifs d'interconnexion et composants passifs à fibres optiques – Procédures fondamentales d'essais et de mesures – Partie 3-35: Examens et mesures – Examen visuel des connecteurs à fibres optiques et des émetteurs-récepteurs à embase fibrée*

3 Termes, définitions et termes abrégés

3.1 Termes et définitions

Aucun terme n'est défini dans le présent document.

L'ISO et l'IEC tiennent à jour des bases de données terminologiques destinées à être utilisées en normalisation, consultables aux adresses suivantes:

- IEC Electropedia: disponible à l'adresse http://www.electropedia.org/
- ISO Online browsing platform: disponible à l'adresse http://www.iso.org/obp

3.2 Termes abrégés

CWDM course wavelength division multiplexing (multiplexage par répartition en longueur d'onde espacée)

DAS data acquisition system (système d'acquisition de données)

DUT device under test (dispositif en essai)

DWDM dense wavelength division multiplexing (multiplexage par répartition en longueur d'onde dense)

ISO optical isolator (isolateur optique)

IL insertion loss (perte d'insertion)

LD laser diode (diode laser)

OSA optical spectrum analyzer (analyseur de spectre optique)

PDL polarization dependent loss (perte dépendant de la polarisation)

RL return loss (affaiblissement de réflexion)

TLS tunable light source (source de rayonnement lumineux accordable)

WDL wavelength dependent loss (perte dépendant de la longueur d'onde)

WDM wavelength division multiplexing (multiplexage par répartition en longueur d'onde)

WWDM wide wavelength division multiplexing (multiplexage par répartition en longueur d'onde large)

4 Appareillage

4.1 Source (S)

Cette unité source est composée d'un émetteur optique de son moyen de connexion et des dispositifs électroniques de commande associés. Une source de rayonnement lumineux accordable (TLS) dans laquelle peut être accordée une longueur d'onde de sortie spécifique peut être choisie en tant qu'émetteur optique. Une source de rayonnement lumineux accordable peut être constituée soit par une diode laser (LD) accordable et un amplificateur optique, soit par un laser à rétroaction fibré. Généralement, les exigences relatives à la puissance et à la stabilité d'un essai nécessitent que l'émetteur optique ait une fibre amorce. Sa stabilité doit être assurée en puissance de sortie et en longueur d'onde/fréquence sur la période de mesure. Pour les dispositifs DWDM, la stabilité en fréquence (au lieu de la stabilité en longueur d'onde) doit avoir une valeur inférieure à la moitié de la largeur de bande du canal. Sauf stipulation contraire de la spécification applicable, la source doit comporter les caractéristiques suivantes:

a) stabilité en longueur d'onde centrale:
   - longueur d'onde centrale nominale ±5 nm (pour les dispositifs WWDM et CWDM);

b) stabilité en fréquence centrale:
   - fréquence centrale nominale ±6,3 GHz (pour les dispositifs DWDM de largeur de bande du canal de 25 GHz);
   - fréquence centrale nominale ±12,5 GHz (pour les dispositifs DWDM de largeur de bande du canal de 50 GHz);
   - fréquence centrale nominale ±25 GHz (pour les dispositifs DWDM de largeur de bande du canal de 100 GHz);

c) stabilité en puissance de sortie:
   - puissance de sortie nominale ±0,05 dB.

4.2 Détecteur optique (D)

L'unité de détection optique est composée d'un détecteur optique, de son moyen de connexion et des dispositifs électroniques associés. Le détecteur doit posséder une plage dynamique suffisante pour réaliser les mesurages nécessaires et il doit être linéaire sur la plage de mesure. Le détecteur doit être stable sur la période de mesure et doit comporter une plage de longueurs d'onde de fonctionnement cohérente avec le DUT. La connexion au détecteur doit se faire avec un adaptateur qui accepte une fiche de connexion de conception appropriée. Le détecteur doit être capable de capturer toute la lumière émise par la partie fiche de connexion. Sauf stipulation

contraire de la spécification applicable, le détecteur doit comporter les caractéristiques suivantes:

– non-linéarité maximale: ≤ ±0,1 dB;
– exactitude, y compris dépendance en polarisation: ≤ ±0,05 dB;
– résolution: ≤ 0,01 dB.

4.3 Enceinte climatique

Le montage d'essai doit inclure une enceinte climatique capable de produire et de maintenir la température et/ou l'humidité spécifiées.

4.4 Système d'acquisition de données (DAS)

L'enregistrement des valeurs de puissance optique lues sur le détecteur optique peut être réalisé soit manuellement soit automatiquement. Un DAS approprié doit être utilisé lorsque les mesurages sont effectués de manière automatique.

4.5 Dispositif de couplage (BD – branching device)

Le rapport de division du dispositif de couplage doit être stable sur les puissances optiques et les longueurs d'onde choisies pour l'essai. Il doit également être insensible à la polarisation. Un rapport de division de 1:99 pour les dispositifs de couplage est recommandé afin d'induire une haute puissance d'entrée au dispositif en essai et une basse puissance au détecteur optique.

4.6 Jonctions temporaires (TJ – temporary joints)

Elles sont généralement utilisées pour raccorder le dispositif en essai à l'appareillage d'essai. Pour les exigences d'essai de puissance et de stabilité optiques, les jonctions temporaires doivent être des épissures par fusion.

4.7 Dispositifs de sécurité

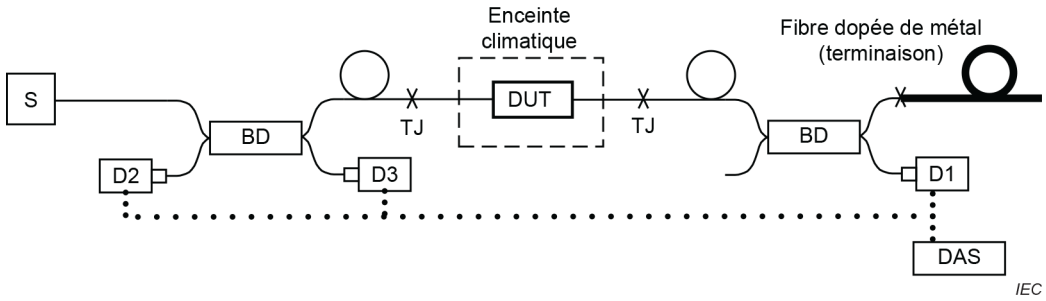
Tous les dispositifs de sécurité nécessaires, y compris les lunettes de sécurité laser, les signaux de sécurité et autres matériels de sécurité, doivent être fournis pour protéger les personnes des risques potentiels encourus au cours des essais.

4.8 Montage d'essai

Pour les composants optiques à deux ports, une disposition type de l'appareillage d'essai est représentée à la Figure 1.

Cette procédure d'essai implique l'utilisation de puissances optiques qui constituent un risque potentiel pour les yeux et la peau du personnel chargé de l'essai. Toutes les procédures de sécurité nécessaires doivent être adoptées conformément à l'IEC 60825-1. En particulier, la puissance doit être coupée (cela signifie qu'il ne doit pas y avoir de propagation de puissance à l'intérieur de la fibre) dans le dispositif en essai lors de tout examen visuel.

Des connecteurs optiques ne doivent pas être utilisés. Des épissures par fusion doivent être utilisées pour tous les points de connexion, comme décrit en 4.6.



Légende

BD dispositif de couplage

D détecteur

DAS système d'acquisition de données

DUT dispositif en essai

S source de rayonnement lumineux

TJ jonction temporaire

Figure 1 – Montage d'essai type de la puissance optique

Pour les dispositifs optiques multiport tels que les dispositifs de couplage, toutes les combinaisons de ports d'entrée et de sortie doivent être soumises à l'essai, sauf stipulation contraire dans la spécification applicable.

Pour les dispositifs WDM, les longueurs d'onde multiples doivent être présentes en entrée en même temps, selon l'application. L'Article A.1 décrit un exemple de montage d'essai pour les dispositifs WDM.

Pour réduire au maximum le matériel d'essai, les DUT peuvent être connectés en série. L'Article A.2 décrit un exemple de montage d'essai pour des DUT connectés en série.

5 Mode opératoire

5.1 Préconditionnement

Les échantillons d'essai choisis doivent être représentatifs du produit normalisé.

Préparer et nettoyer les DUT conformément aux instructions du fabricant. Un examen visuel doit être entrepris conformément à l'IEC 61300-3-1 et à l'IEC 61300-3-35. Les débris ou la présence de contamination sont l'une des principales causes de défaillance dans les applications de connecteurs de puissance optique élevée.

NOTE L'IEC TR 62627-01 décrit des méthodes de nettoyage des connecteurs fibroniques.

Sauf indication contraire dans la spécification applicable, préconditionner le DUT pendant 2 h ou plus dans les conditions atmosphériques normales définies dans l'IEC 61300-1.

5.2 Mesurages et examens initiaux

Effectuer les mesurages et les examens initiaux sur le DUT, comme exigé dans la spécification applicable. Les résultats du mesurage initial doivent être compris dans les limites établies par la spécification applicable.

5.3 Conditionnement

a) Placer l'enceinte et le DUT en conditions atmosphériques normales. Mettre le DUT dans l'enceinte dans sa position de fonctionnement normale. Lorsque cela est exigé, les